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MASTER FILE

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DSSD CENSUS 2000 PROCEDURES AND OPERATIONS MEMORANDUM SERIES
CHAPTER #LL-4

MEMORANDUM FOR Michael J. Longini
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Subject: Long Form Conversion Processing for the Sample Tolerance Check in Census 2000

I. Introduction

The Sample Tolerance Check (STC) is an operation that will occur in List/Enumerate (L/E) areas as part of Census 2000. It is designed to detect enumerator bias that may be introduced into the long form sample if an enumerator does not follow the predesignated sampling pattern found on the listing pages of the address register[1].

The automated STC software prepared by the Technologies Management Office (TMO) will be run immediately after all L/E assignment areas (AAs) have been completed. The results of the STC for a given AA may be: 1) no action required; 2) the long form sample must be reselected; or 3) additional long form sample must be selected. For results 2 and 3, selected addresses originally interviewed with a short form will be reinterviewed with a long form. To do this, the STC software will select a sample of short form addresses within the AA and, as part of the field followup, these addresses will be reinterviewed with a long form. The long form questionnaires used in this operation will have the replacement box checked so that they will be selected over the short form questionnaire previously submitted during the Primary Selection Algorithm (PSA) process.

[1] For further details of the STC methodology, see DSSD Census 2000 Procedures and Operations Memorandum Series Chapter #LL- 1, "*Sample Tolerance Check Specifications for Census 2000*".

For result 2 of the STC, selected addresses interviewed with a long form will be converted to a short form. To do this, the STC software will select a sample of long form addresses within the AA. The following sections specify the processing for these cases by the Decennial Systems and Contracts Management Office (DSCMO).

Any questions regarding this memorandum should be directed to Philip Gbur (457-4206, Room 2402A-2) or Steven Hefter (457-4082, Room 2121-2).

II. Files

A. From TMO

X File: An address level STC output file created for each L/E AA containing the following information (provide DSCMO with a record layout):

State
County
STC batch number (to be determined by the TMO)
L/E AA
AA Sampling Rate
STC result (pass/fail)
Processing ID
Initial designated form type
Post-STC designated form type
Number of people enumerated at the address (before any STC reinterviewing)

B. Within DSCMO

Y File: Address level file which identifies form type for each address

III. DSCMO Processing

Match the records on the X and Y files by processing ID. For each matching record that was originally a short form and the STC converted to a long form, set a *CONVERT* flag on the Y file to "1" . For each matching record originally a long form that the STC converted to a short form set *CONVERT*= "2". For records retaining their original form type desigination set *CONVERT*= "0". Provide the Decennial Statistical Studies Division (DSSD) access to the X and Y files and their record layouts for verification.

After the DSSD verification of the flag, delete the sample data for all records with a *CONVERT* flag value of "2". Treat these cases as short forms in all further processing.

cc: DSSD Census 2000 Procedures and Operations Memorandum Series Distribution List
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